

In the United States Patent and Trademark Office

In re the application of
Lee D. Whetsel

TI-31203.1

Application No. 10/806,546

Art Unit: 2829

Filed: March 23, 2004

Examiner: Jimmy Nguyen

Title: Semiconductor Test System and Method

March 8, 2006

Asst. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313

MAILING CERTIFICATE UNDER 37 C.F.R. §1.8(A)
I hereby certify that the above correspondence is
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First Class Mail in an envelope addressed to:
Assistant Commissioner for Patents, P.O. Box 1450,
Alexandria, VA 22313-1450 on March 8, 2006.

Lawrence J. Bassuk, Reg. No. 29,043

Dear Sir:

Transmitted herewith is an amendment in this application.

The fee has been calculated as shown below.

CLAIMS AS AMENDED						
	CLAIMS REMAINING AFTER AMENDMENT		HIGHEST NUMBER PREVIOUSLY PAID FOR	PRESENT EXTRA	RATE	ADDITIONAL FEE
Total Claims	4	Minus	20	= 0	x \$50 =	\$ 0
Ind. Claims	1	Minus	3	= 0	x \$200 =	\$ 0
TOTAL ADDITIONAL FEE FOR THIS AMOUNT						\$ 0

Under 37 C.F.R. § 1.16(k) please charge the total additional fee, and any further fees, or credit overpayment to Deposit Account No. 20-0668, of Texas Instruments Incorporated.

Respectfully submitted

Texas Instruments Incorporated
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Dallas, Texas 75265
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Lawrence J. Bassuk
Reg. No. 29,043
Attorney for Applicant



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Amendment C Under 37 CFR 1.111

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Lawrence J. Bassuk
Lawrence J. Bassuk, Reg. No. 29,043

Dear Sir:

Responsive to the Examiner's Actions of 9/21/2005 and
12/15/2005, please amend this application as follows:

In the Title:

Amend the title as follows:

SEMICONDUCTOR TEST SYSTEM AND METHOD PROCESS APPLYING
RESPONSE SIGNALS TO OUTPUTS AND COMPARING ON DIE